Call for Papers

September 8, 9, 10, 11, 1986
The Sheraton Washington Hotel,
Washington, D.C.
Sponsored by the IEEE Philadelphia Section and the IEEE Computer Society

TESTING'S IMPACT ON DESIGN & TECHNOLOGY

Topics of interest include, but are not limited to, the following areas:

- Testability Measures & Fault Analysis
- Test Generation & Design Validation
- Memory Test
- Microprocessor & VLSI Test
- Wafer Scale Integrated Test
- Test Equipment & Methods
- Design for Testability
- Analog & Hybrid Test
- Test Software
- Software and Microcode Test
- Surface Mounted Component Assembly and Test
- Built-In Self-Test
- Test Economics
- Quality & Reliability
- System & Field Test
- Board Test
- Process & Test Data Management
- Test Engineering Management
- Artificial Intelligence Applications to Test
- Test Fixturing
- Applications of Computer Aided Engineering to Test
- Future Trends

This conference is the major technical forum on the testing of semiconductor components, boards and systems. Emphasis is on methods for testing increasingly complex VLSI/wafer scale devices and assemblies. The Conference encourages the open discussion of test problems and of the role of test professionals in implementing solutions.

Formal technical sessions and workshops are planned. Original technical papers are required for the technical sessions. Short position papers will be required from each workshop participant. All papers will be published in the Conference Proceedings. Late breaking developments may be presented in poster sessions. Informal evening sessions are also planned.

Those interested in presenting a paper should submit either a full manuscript, or a 35-word abstract and a minimum 500-word paper outline and conclusions (double-spaced) in ten copies to the appropriate address below. Full manuscript submissions are preferred.

The paper submission deadline is February 1, 1986, for Europe and Asia; February 15, 1986, for the U.S.A. Authors of accepted papers will be notified during May, 1986, and will receive an author's kit, including special typing mats. The final typed papers to be published in the Conference Proceedings should contain at least 1500 words and are due June 6, 1986. Late submission or prior publication will cause for rejection.

Those interested in serving as a panelist or workshop member should contact the Program Chairman by March 1, 1986.

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Suggestions for additional topics or technical paper sessions are welcomed. Please contact the Program Chairman by Feb. 1, 1986.